Workshop

„Advanced X-ray Diffraction for Semiconductor Materials and Technology“

Date: April 03-04, 2014
Location: IHP, Frankfurt (Oder), conference room, level D1

Agenda

Thursday, 03.04.2014

13:30 - 13:45 Welcome and short introduction of IHP
13:45 - 14:30 U. Pietsch
- X-ray analysis of phase structure of single GaAs nanowires grown by self-catalysed MBE onto Silicon (111) substrate
14:30 - 15:15 P. Zaumseil
- Recent X-ray activities at IHP
15:15 - 15:30 Break
15:30 - 16:15 J. Grenzer
- In-situ X-ray experiments for material science
16:15 - 17:00 M. Hanke
- Synchrotron-based x-ray scattering - a versatile tool to study low-dimensional structures
18:30 Dinner in Frankfurt (Oder)
Friday, 04.04.2014

09:00 - 09:45  J. Stangl  
*Strained nanostructures seen by focused x-rays*

09:45 - 10:30  A. Dommann  
*HRXRD analysis on Ge Devices*

10:30 - 10:45  Break

10:45 - 11:30  T. Schülli  
*New microscopy opportunities for X-rays: 5D imaging in real and reciprocal space*

11:30 - 12:15  M. Schmidbauer  
*Piezoelectric domains in NaNbO3 epitaxial thin films studied by x-ray diffraction*

12:30  Lunch at IHP

After lunch: Possibilities to visit different laboratories at IHP